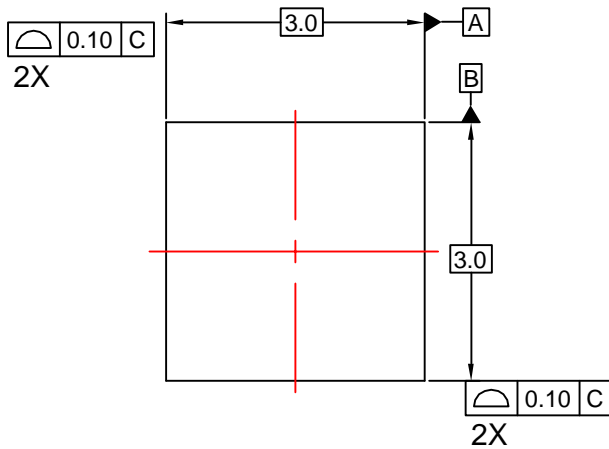
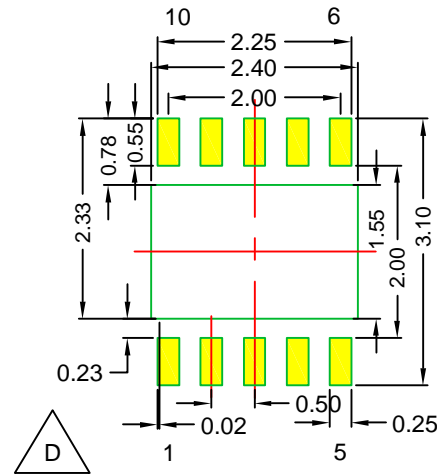


REVISIONS

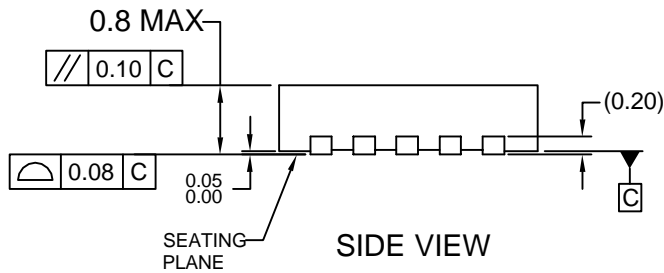
LTR	DESCRIPTION	EDCN	DATE	BY/APP'D
A	RELEASE TO DOCUMENT CONTROL		18-9-2003	FEITAN
B	CORRECTED DAP DIMENSIONAL ERRORS, UPDATED JEDEC REF, ADJUSTED LAND PATTERN	MASS ECDN UPDATE	17-APR-2006	H.ALLEN



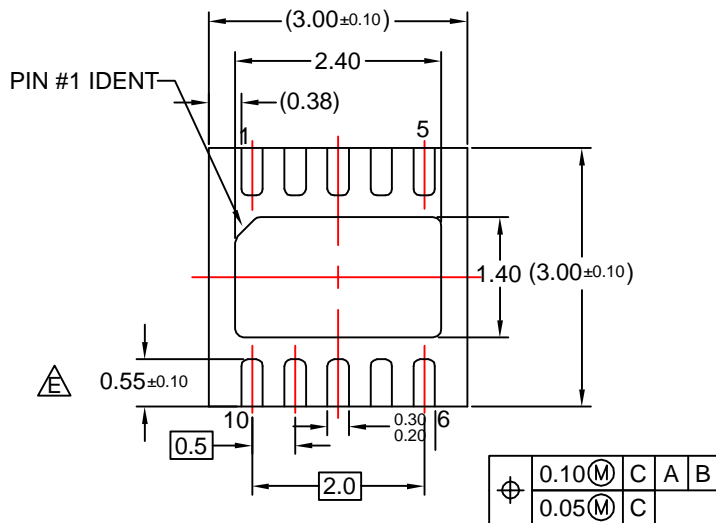
TOP VIEW



RECOMMENDED LAND PATTERN



SIDE VIEW



BOTTOM VIEW

NOTES:

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION WEED-5 EXCEPT WHERE NOTED
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- LAND PATTERN DIMENSIONS ARE NOMINAL REFERENCE VALUES ONLY
- NOT COMPLIANT

MLP10ArevB

APPROVALS		DATE	FAIRCHILD SEMICONDUCTOR™			
DRAWN	FEITAN	8-9-2003	Bayan Lepas, FIZ, 11900, Penang, Malaysia.			
DFTG. CHK.	H.ALLEN	09-11-2005	10LD, MLP, DUAL, JEDEC MO-229, 3MM SQUARE			
ENGR. CHK.	J.KINGSBURY	29-11-2005				
			SCALE	SIZE	DRAWING NUMBER	REV
			N/A	N/A	MKT-MLP10A	B
			DO NOT SCALE DRAWING		SHEET 1 of 1	